

<b>Notice of References Cited</b>	Application/Control No. 10/541,772		Applicant(s)/Patent Under Reexamination HATA ET AL.	
	Examiner ALI SOROUSH		Art Unit 1616	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0163877	09-2003	Baker et al.	8/405
	B	US-			
	C	US-			
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	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	JP-358124713-A	07-1983	Japan	Mizakumi et al.	A61K007/13
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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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